Microwave Faraday Rotation in Molybdenum Disulfide

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Citation Report

#	Article	IF	CITATIONS
1	Vertical dielectric screening of few-layer van der Waals semiconductors. Nanoscale, 2017, 9, 14540-14547.	5.6	20
2	Theoretical investigation of the vertical dielectric screening dependence on defects for few-layered van der Waals materials. RSC Advances, 2019, 9, 40309-40315.	3.6	12